

MOSFET - Power, Single P-Channel

-40 V, 13.5 mΩ, -53 A

Product Preview

NVTYS014P04M8L

Features

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR–Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit			
Drain-to-Source Voltage			V_{DSS}	-40	V			
Gate-to-Source Voltage	Э		V_{GS}	±20	V			
Continuous Drain		T _C = 25°C	I _D	-53	Α			
Current R _{θJC} (Notes 1, 2, 4)	Steady	T _C = 100°C		-39				
Power Dissipation	State	T _C = 25°C	P_{D}	88	W			
R _{θJC} (Notes 1, 2)		T _C = 100°C	1	44]			
Continuous Drain	$\begin{array}{c} T_A = 25^{\circ}C & I_D \\ \\ \text{Steady} \\ \text{State} & T_A = 100^{\circ}C \\ \\ T_A = 25^{\circ}C & P_D \\ \\ T_A = 100^{\circ}C \end{array}$	T _A = 25°C	I _D	-10.4	Α			
Current R _{0JA} (Notes 1, 3, 4)			-7.3					
Power Dissipation		State	State	State	T _A = 25°C	P_{D}	3.1	W
R _{θJA} (Notes 1, 3)		T _A = 100°C		1.6				
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I _{DM}	210	Α			
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +175	°C			
Source Current (Body Diode)			I _S	50.6	Α			
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C			

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

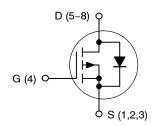
Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Drain) (Notes 1, 2, 4)	$R_{ heta JC}$	2.47	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	38.7	

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- Assumes heat-sink sufficiently large to maintain constant case temperature independent of device power.
- 3. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

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V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
-40 V	13.5 m Ω @ –10 V	-53 A
-40 V	20 mΩ @ -4.5 V	-30 A

P-Channel MOSFET





3.3x3.3 CASE 760AD

MARKING DIAGRAM

014P 04M8L AWLYW

014P04M8L = Specific Device Code

A = Assembly Location
WL = Wafer Lot

WL = Water Lot Y = Year WW = Work Week

ORDERING INFORMATION

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

This document contains information on a product under development. **onsemi** reserves the right to change or discontinue this product without notice.

ELECTRICAL CHARACTERISTICS ($T_J = 25$ °C unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	· · · · · · · · · · · · · · · · · · ·				-		-
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} = 0 V, I_{D} = 250 μA		-40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				21.6		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 \text{ V}, \ V_{DS} = -40 \text{ V}$				-1.0	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D =	420 μA	-1		-3	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				-4.5		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = -10 V, I _E	₀ = -25 A		10.5	13.5	mΩ
		V _{GS} = -4.5 V, I	_D = -20 A		14.6	20	
CHARGES AND CAPACITANCES							
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V, f} = 100 \text{ KHz,}$ $V_{DS} = -25 \text{ V}$			1690		pF
Output Capacitance	C _{oss}				595		
Reverse Transfer Capacitance	C _{rss}				23		
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = -10 \text{ V}, V_{DS} = -20 \text{ V},$ $I_D = -25 \text{ A}$			27		nC
Threshold Gate Charge	Q _{G(TH)}				2.0		
Gate-to-Source Charge	Q_{GS}				4.5		-
Gate-to-Drain Charge	Q_{GD}				8		
SWITCHING CHARACTERISTICS, V_G	s = -10 V (Note	6)					
Turn-On Delay Time	t _{d(on)}				8		ns
Rise Time	t _r	V_{GS} = -10 V, V_{DS} = -20 V, I_{D} = -25 A, R_{G} = 6 Ω			4		
Turn-Off Delay Time	t _{d(off)}				126		
Fall Time	t _f				48		
DRAIN-SOURCE DIODE CHARACTER	RISTICS						
Forward Diode Voltage	V_{SD}	$V_{GS} = 0 \text{ V},$ $I_{S} = -25 \text{ A}$ $T_{J} = 25^{\circ}\text{C}$ $T_{J} = 175^{\circ}\text{C}$			-0.9	-1.25	V
					-0.73		
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = -25 \text{ A}$			38		ns
Charge Time	t _a				19		1
Discharge Time	t _b				20		1
Reverse Recovery Charge	Q_{RR}				26	40	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.

6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

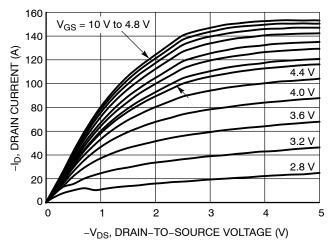


Figure 1. On-Region Characteristics

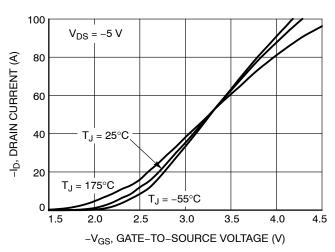


Figure 2. Transfer Characteristics

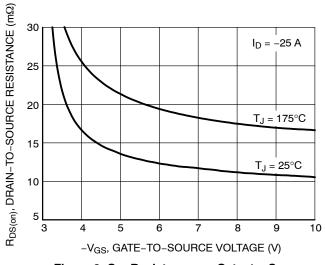


Figure 3. On-Resistance vs. Gate-to-Source Voltage

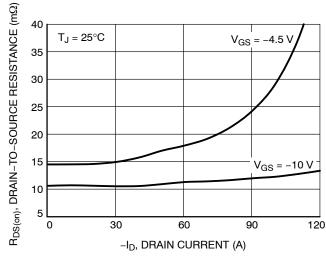


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

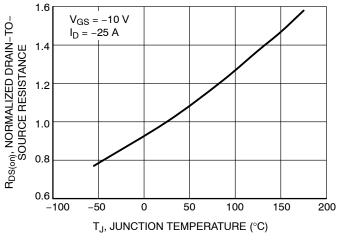


Figure 5. On–Resistance Variation with Temperature

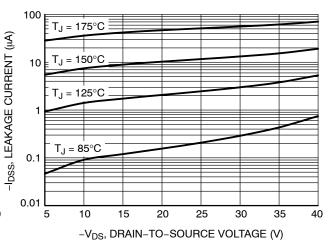


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

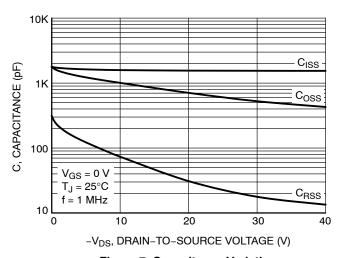


Figure 7. Capacitance Variation

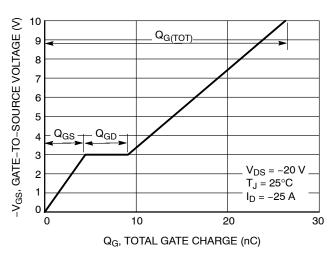


Figure 8. Gate-to-Source Voltage vs. Total Charge

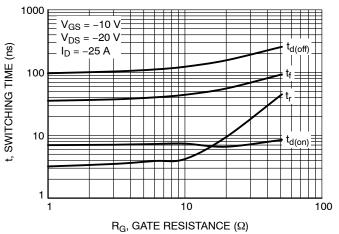


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

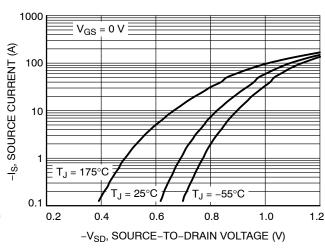


Figure 10. Diode Forward Voltage vs. Current

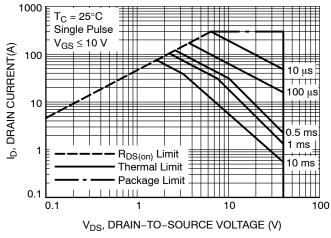


Figure 11. Maximum Rated Forward Biased Safe Operating Area

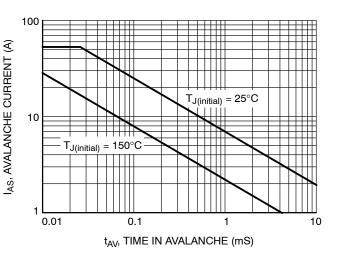


Figure 12. Maximum Drain Current vs. Time in Avalanche

TYPICAL CHARACTERISTICS

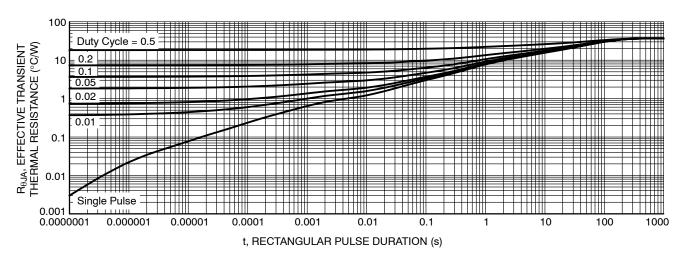


Figure 13. Thermal Response

DEVICE ORDERING INFORMATION

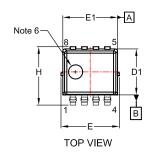
Device	Marking	Package	Shipping [†]
NVTYS014P04M8LTWG	014P 04M8L	LFPAK33	3000 / Tape & Reel

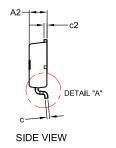
[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

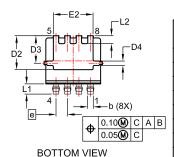
PACKAGE DIMENSIONS

LFPAK8 3.3x3.3, 0.65P

CASE 760AD ISSUE E









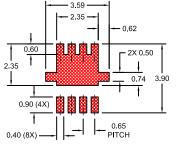


- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS OR BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- 4. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H
- 6. OPTIONAL MOLD FEATURE.

DIM	MILLIMETERS				
Diivi	MIN.	NOM.	MAX.		
Α	0.95	1.05	1.15		
A1	0.00	0.05	0.10		
A2	0.95	1.00	1.05		
А3		0.15 RE	F		
b	0.27	0.32	0.37		
С	0.12	0.17	0.22		
c2	0.12	0.17	0.22		
D1	2.50	2.60	2.70		
D2	1.82	1.92	2.02		
D3	1.46	1.56	1.66		
D4	0.20	0.25	0.30		
Е	3.20	3.30	3.40		
E1	3.00	3.10	3.20		
E2	2.15	2.25	2.35		
е	0.65 BSC				
Н	3.20	3.30	3.40		
L	0.25	0.37	0.50		
L1	0.48	0.58	0.68		
L2	0.35	0.45	0.55		
Q	0.45	0.50	0.55		
А	٥°	4°	8°		

NAUL INAUTEDO

(A3) Q A1
DETAIL 'A' SCALE: 2:1
3.59



LAND PATTERN RECOMMENDATION

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